ULTRA FAST RECOVERY POWER RECTIFIER



1N6626D3A / 1N6626D3B 1N6626D3C / 1N6626D3D

- High Reliability Screening Options Available.
- High forward current surge current capability.
- Switching power supplies or other applications requiring fast switching and low forward loss.
- Variants D3C & D3D with solder dip finished pads (63Sn/37Pb).



ABSOLUTE MAXIMUM RATINGS (T_A = 25°C unless otherwise stated)

V _{RWM}	Working Peak Reverse Voltage	200V
I_{O}^{1}	Average Rectified Forward Current $T_A = 25^{\circ}C$	1.75A
I_{FSM^2}	Peak Forward Current Surge	75A
TJ	Junction Temperature Range	-65 to +175°C
T_{stg}	Storage Temperature Range	-65 to +175°C
T_{SP}	Maximum Soldering Pad Temperature for 20s	260°C

THERMAL PROPERTIES

Symbols	Parameters	Max.	Units
R ₀ JSP(IN)	Thermal Resistance, Junction To Solder Pads $T_{SP} = 25^{\circ}C$	40	°C/W
R ₀ JA(PCB) ⁽³⁾	Thermal Resistance, Junction To Ambient, On PCB	72.5	°C/W
R ₀ JA(PCB)(4)	Thermal Resistance, Junction To Ambient, On PCB	110	°C/W

Notes

- (1) I_{O1} is rated at 1.75A @ $T_A = 25$ °C for PC boards where thermal resistance from mounting point to ambient is sufficiently controlled where $T_{I}(Max)$ does not exceed 175°C; This equates to $R_{\Theta JA(PCB)} \le 85$ °C/W.
- (2) $T_A = 25$ °C @ IO=0A and VRWM = 0V for ten 8.3mS surges at 1 minute intervals.
- (3) PCB = FR4, 0.0625 Inch (1.59mm) thick, single layer, 1.0-Oz Cu, Pad Size, (1.0" x 1.0"), (645mm x 645mm), horizontal in still air.
- (4) PCB = FR4, 0.0625 Inch (1.59mm) thick, single layer, 1.0-Oz Cu, Pad Size, (0.070" x 0.155")‡, (1.78mm x 3.94mm) ‡, horizontal in still air. $I_{O.1}$ is rated at 1.5A @ I_A = 25°C for PC boards where $R_{\theta JA(PCB)} \le 111$ °C/W. Derate at 10mA/°C above I_A = 25°C in this case.
- ‡ Recommended solder pad layout dimensions for this device, as detailed within this datasheet for the D-5A device.



ULTRA FAST RECOVERY POWER RECTIFIER 1N6626D2A/B/C/D



ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise stated)

Symbol	Parameters	Test Conditions		Min.	Тур.	Max.	Unit
	Diada Famuand Valtaga	I _F = 4A				1.5	
V_{F}^{3}	Diode Forward Voltage	I _F = 2A	I _F = 2A			1.35	V
			T _A = -65°C			1.65	
I _R ³	Reverse Current Leakage	V _R = 200V	T _A = 25°C			2.0	Δ
			T _A = 150°C			500	μΑ
V _{BR} ³	Breakdown Voltage	I _R = 50μA	•	220			\ /
			T _A = -65°C	200			V

DYNAMIC CHARACTERISTICS

C _T	Capacitance	$V_R = 10V$ $f = 1.0MHz$		60	pF
^t rr1 ⁴	Low Current Reverse Recovery Time	$I_F = 0.5A$, $I_{RM} = 1.0A$, $I_{R(REC)} = 0.25A$	30		ns
V _{FRM}	Forward Recovery Voltage	$I_F = 1A$ $t_r = 12ns$		8	V

Notes

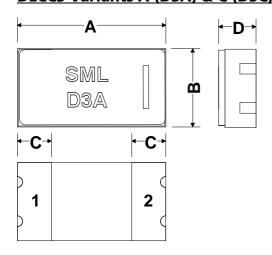
 $^{^3}$ Pulse Width ≤ 300us, δ ≤ 2%

⁴As per MIL-STD-750 Method 4031 Condition B.



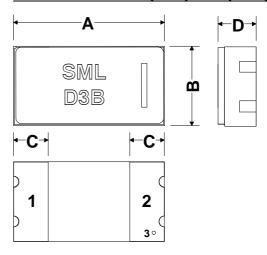
MECHANICAL DATA

DLCC3 Variants A (D3A) & C (D3C)



DIMENSION	mm	Inches
А	7.00 ±0.10	0.275 ±0.004
В	3.75 ±0.10	0.143 ±0.004
С	1.60 ±0.10	0.063 ±0.004
D	1.76 ±0.10	0.069 ±0.004

DLCC3 Variants B (D3B) & D (D3D)

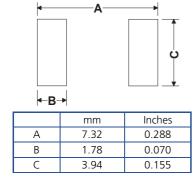


PACKAGE VARIANT / PART NUMBER TABLE

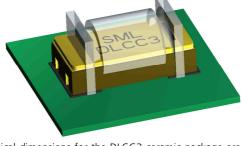
Variant	Pad 1	Pad 2	Pad 3	Pad Finish	Order Part No.
Α	Anode	Cathode	No Pad (2 Pad)	Au Finished	1N6626D3A
В	Anode	Cathode	Lid Contact To Anode*	Au Finished	1N6626D3B
C	Anode	Cathode	No Pad (2 Pad)	Hot Solder Dip - 63Sn/37Pb	1N6626D3C
D	Anode	Cathode	Lid Contact To Anode*	Hot Solder Dip - 63Sn/37Pb	1N6626D3D

- * The additional contact provides a connection to the lid in the application. Connecting the metal lid to a known electrical potential stops deep dielectric discharge in space applications; see the Space Weather link www.semelab.co.uk/dlcc3.html on the Semelab web site. Package variant to be specified at order.
- † The DLCC3 package design takes full advantage of the proven high reliability pedigree of the HTCC surface mount packaging technology, which is easily integrated for automated assembly. Semelab has taken the existing standards for ceramic surface mount package manufacture and added additional design features to enhance thermal performance, to present a competitive alternative for high reliability applications.

SOLDER PAD LAYOUT



Soldering temperature should be 260°C for a maximum of 10 seconds.



The physical dimensions for the DLCC3 ceramic package are designed to be different from the published dimensions for the "D-5B" and "E-MELF" outlines. The DLCC3 design fully utilises the recommended solder footprint for the "D-5B" / "E-MELF" Package, and as such presents a drop in replacement for existing board designs.

PACKAGE MASS

Gold Plated Solder Pad Finish = 150mg

ULTRA FAST RECOVERY POWER RECTIFIER 1N6626D2A/B/C/D



SCREENING OPTIONS

Space Level (JQRS/ESA) and High Reliability options are available in accordance with the <u>High Reliability and Screening Options Handbook</u> available for download from the from the TT electronics Semelab web site.

ESA Quality Level Products are based on the testing procedures specified in the generic ESCC 5000 and in the corresponding part detail specifications.

Semelab's QR216 and QR217 processing specifications (JQRS), in conjunction with the companies ISO 9001:2000 approval present a viable alternative to the American MIL-PRF-19500 space level processing.

QR217 (Space Level Quality Conformance) is based on the quality conformance inspection requirements of MIL-PRF-19500 groups A (table V), B (table VIa), C (table VII) and also ESA / ESCC 5000 (chart F4) lot validation tests.

QR216 (Space Level Screening) is based on the screening requirements of MIL-PRF-19500 (table IV) and also ESA /ESCC 5000 (chart F3).

JQRS parts are processed to the device data sheet and screened to QR216 with conformance testing to Q217 groups A and B in accordance with MIL-STD-750 methods and procedures.

Additional conformance options are available, for example Pre-Cap Visual Inspection, Buy-Off Visit or Data Packs. These are chargeable and must be specified at the order stage (See Ordering Information). Minimum order quantities may apply.

Alternative or additional customer specific conformance or screening requirements would be considered. Contact Semelab sales with enquires.

MARKING DETAILS

Parts can be laser marked with approximately 7 characters on two lines and always includes cathode identification. Typical marking would include part or specification number, week of seal or serial number subject to available space and legibility.

Customer specific marking requirements can be arranged at the time of order.

Example Marking:



ORDERING INFORMATION

Part numbers are built up from Type, Package Variant, and screening level. The part numbers are extended to include the additional options as shown below.

Type – See Main Part Number Package Variant – See Mechanical Data Screening Level – See Screening Options (ESA / JQRS)

Additional Options:

Customer Buy-Off visit .CVB Data Pack .DA Solderability Samples .SS Scanning Electron Microscopy .SEM Radiography (X-ray) .XRAY Total Dose Radiation Test .RAD MIL-PRF-19500 (QR217) Group B charge .GRPB Group B destructive mechanical samples .GBDM (12 pieces) Group C charge .GRPC Group C destructive electrical samples .GCDE (12 pieces) Group C destructive mechanical samples .GCDM (6 pieces) ESA/ESCC Lot Validation Testing (subgroup 1) charge .LVT1 LVT1 destructive samples (environmental) .L1DE (15 pieces) LVT1 destructive samples (mechanical) .L1DM (15 pieces) Lot Validation Testing (subgroup 2) charge .LVT2 LVT2 endurance samples (electrical) .L2D (15 pieces) Lot Validation Testing (subgroup 3) charge .LVT3 LVT3 destructive samples (mechanical) .L3D (5 pieces)	Customer Pre-Cap Visual Inspection	.CVP
Solderability Samples Scanning Electron Microscopy Radiography (X-ray) Total Dose Radiation Test MIL-PRF-19500 (QR217) Group B charge Group B destructive mechanical samples Group C charge Group C destructive electrical samples Group C destructive mechanical samples ESA/ESCC Lot Validation Testing (subgroup 1) charge LVT1 destructive samples (environmental) L1DE (15 pieces) LVT1 destructive samples (mechanical) LVT2 endurance samples (electrical) Lot Validation Testing (subgroup 3) charge LVT3 LVT3	Customer Buy-Off visit	.CVB
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Radiography (X-ray) Total Dose Radiation Test MIL-PRF-19500 (QR217) Group B charge Group C charge Group C destructive mechanical samples Group C destructive electrical samples Group C destructive mechanical samples Group C destructive mechanical samples GRPC Group C destructive mechanical samples GCDE (12 pieces) ESA/ESCC Lot Validation Testing (subgroup 1) charge LVT1 LVT1 destructive samples (environmental) LVT1 destructive samples (mechanical) LVT1 destructive samples (mechanical) LVT2 LVT2 endurance samples (electrical) Lot Validation Testing (subgroup 3) charge LVT3	Solderability Samples	.SS
Total Dose Radiation Test	Scanning Electron Microscopy	.SEM
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Group B chargeGRPB Group B destructive mechanical samplesGBDM (12 pieces) Group C chargeGRPC Group C destructive electrical samplesGCDE (12 pieces) Group C destructive mechanical samplesGCDM (6 pieces) ESA/ESCC Lot Validation Testing (subgroup 1) chargeLVT1 LVT1 destructive samples (environmental)L1DE (15 pieces) LVT1 destructive samples (mechanical)L1DM (15 pieces) Lot Validation Testing (subgroup 2) chargeLVT2 LVT2 endurance samples (electrical)L2D (15 pieces) Lot Validation Testing (subgroup 3) chargeLVT3	Total Dose Radiation Test	.RAD
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Group C chargeGRPC Group C destructive electrical samplesGCDE (12 pieces) Group C destructive mechanical samplesGCDM (6 pieces) ESA/ESCC Lot Validation Testing (subgroup 1) chargeLVT1 LVT1 destructive samples (environmental)L1DE (15 pieces) LVT1 destructive samples (mechanical)L1DM (15 pieces) Lot Validation Testing (subgroup 2) chargeLVT2 LVT2 endurance samples (electrical)L2D (15 pieces) Lot Validation Testing (subgroup 3) chargeLVT3	Group B charge	.GRPB
Group C destructive electrical samples .GCDE (12 pieces) Group C destructive mechanical samples .GCDM (6 pieces) ESA/ESCC Lot Validation Testing (subgroup 1) charge .LVT1 LVT1 destructive samples (environmental) .L1DE (15 pieces) LVT1 destructive samples (mechanical) .L1DM (15 pieces) Lot Validation Testing (subgroup 2) charge .LVT2 LVT2 endurance samples (electrical) .L2D (15 pieces) Lot Validation Testing (subgroup 3) charge .LVT3	Group B destructive mechanical samples	.GBDM (12 pieces)
Group C destructive mechanical samples .GCDM (6 pieces) ESA/ESCC Lot Validation Testing (subgroup 1) charge .LVT1 LVT1 destructive samples (environmental) .L1DE (15 pieces) LVT1 destructive samples (mechanical) .L1DM (15 pieces) Lot Validation Testing (subgroup 2) charge .LVT2 LVT2 endurance samples (electrical) .L2D (15 pieces) Lot Validation Testing (subgroup 3) charge .LVT3	Group C charge	.GRPC
ESA/ESCC Lot Validation Testing (subgroup 1) charge	Group C destructive electrical samples	.GCDE (12 pieces)
Lot Validation Testing (subgroup 1) charge	Group C destructive mechanical samples	.GCDM (6 pieces)
LVT1 destructive samples (environmental)L1DE (15 pieces) LVT1 destructive samples (mechanical)L1DM (15 pieces) Lot Validation Testing (subgroup 2) chargeLVT2 LVT2 endurance samples (electrical)L2D (15 pieces) Lot Validation Testing (subgroup 3) chargeLVT3	ESA/ESCC	
LVT1 destructive samples (mechanical) .L1DM (15 pieces) Lot Validation Testing (subgroup 2) charge .LVT2 LVT2 endurance samples (electrical) .L2D (15 pieces) Lot Validation Testing (subgroup 3) charge .LVT3	Lot Validation Testing (subgroup 1) charge	.LVT1
Lot Validation Testing (subgroup 2) charge	LVT1 destructive samples (environmental)	.L1DE (15 pieces)
LVT2 endurance samples (electrical) .L2D (15 pieces) Lot Validation Testing (subgroup 3) charge .LVT3	LVT1 destructive samples (mechanical)	.L1DM (15 pieces)
Lot Validation Testing (subgroup 3) charge .LVT3	Lot Validation Testing (subgroup 2) charge	.LVT2
	LVT2 endurance samples (electrical)	.L2D (15 pieces)
LVT3 destructive samples (mechanical) .L3D (5 pieces)		.LVT3
	LVT3 destructive samples (mechanical)	.L3D (5 pieces)

Additional Option Notes:

- 1) All 'Additional Options' are chargeable and must be specified at order stage.
- 2) When Group B,C or LVT is required, additional electrical and mechanical destructive samples must be ordered
- 3) All destructive samples are marked the same as other production parts unless otherwise requested.

Example ordering information:

The following example is for the 1N6626 part with package variant D (lid contact to anode, 63Sn/37Pb terminal finish), JQRS screening, additional Group C conformance testing and a Data pack.

Part Numbers:

1N6626D3D-JQRS (Include quantity for flight parts) 1N6626D3D.GRPC (chargeable conformance option) 1N6626D3D.GCDE (charge for destructive parts) 1N6626D3D.GCDM (charge for destructive parts) 1N6626D3D.DA (charge for Data pack)

Website: http://www.semelab-tt.com

Customers with any specific requirements (e.g. marking or screening) may be supplied with a similar alternative part number (there is maximum 20 character limit to part numbers). Contact Semelab sales with enquiries.

High Reliability and Screening Options Handbook link: http://www.semelab.co.uk/pdf/misc/documents/hirel_and_screening_options.pdf

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